

Notice of References Cited	Application/Control No. 10/541,815		Applicant(s)/Patent Under Reexamination GERLT ET AL.	
	Examiner MATTHEW W. SUCH		Art Unit 2891	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,958,270	10-2005	Misra et al.	438/257
*	C	US-6,908,536	06-2005	Beckmann, Udo	204/412
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	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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*	U	Roth, K.M., et al. "Characterization of Charge Storage in Redox-Active Self-Assembled Monolayers." LANGMUIR, Vol. 18 (2002): pp. 4030-4040.
*	V	Roth, K.M., et al. "Molecular Approaches Toward Information Storage Based on the Redox Properties of Porphyrins in Self-Assembled Monolayers." J. VAC. SCI. TECHNOL. B, Vol. 18, No. 5 (Sep/Oct 2000): pp. 2359-2364.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.